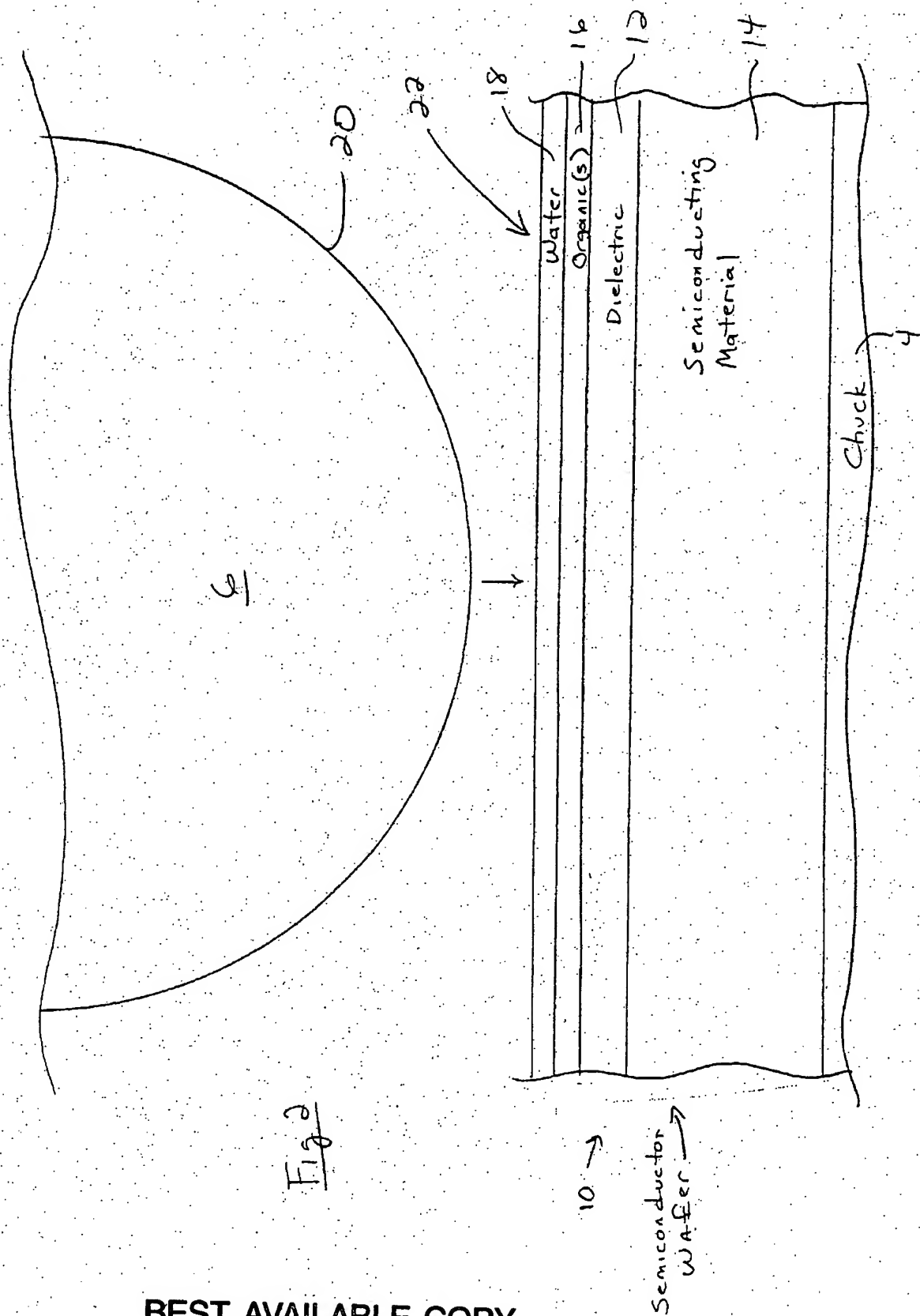


Inventors: William H. Howland, Jr. and Christine E. Kalnas  
 "METHOD AND APPARATUS FOR DETERMINING THE DIELECTRIC CONSTANT OF A LOW  
 PERMITTIVITY DIELECTRIC ON A SEMICONDUCTOR WAFER"

Attorney Docket No.: 1880-031569



BEST AVAILABLE COPY

3  
F-2

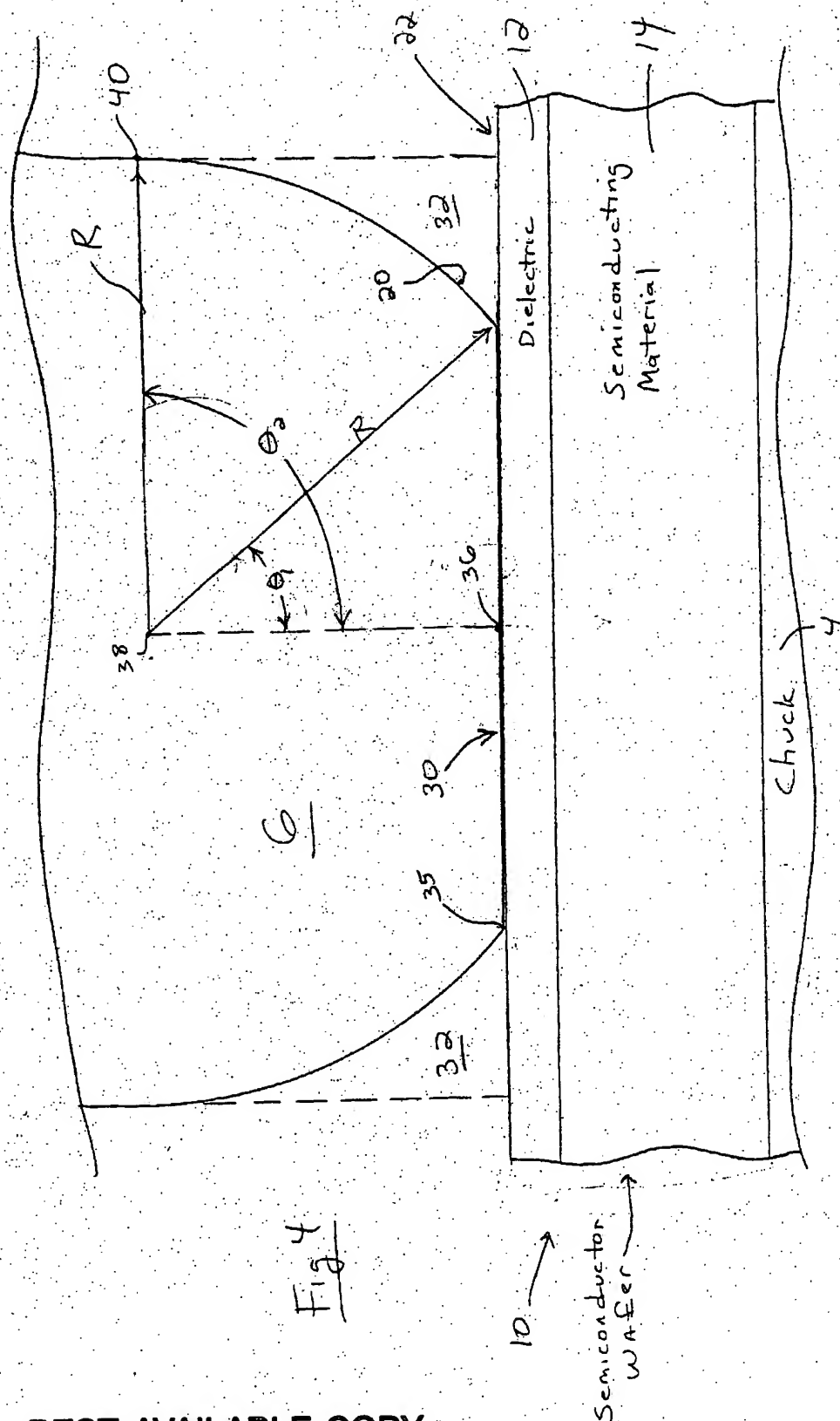


Fig. 4